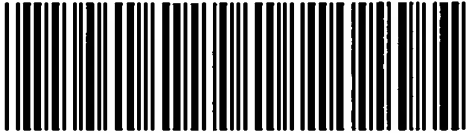


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/080,795	KAMME ET AL.	
	Examiner	Art Unit	
	Young J. Kim	1637	

SEARCHED			
Class	Subclass	Date	Examiner
435	6	6/6/2005	YJK
	91.1	6/6/2005	YJK
	91.2	6/6/2005	YJK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	6/6/2005	YJK
STN Commercial Databases (Biosis, Medline, Embase, Embal, SciSearch, CAPlus)	6/6/2005	YJK
See enclosed for search strategies	6/6/2005	YJK